

**July 2017** 



# IEEE Council on Electronic Design Automation

### IEEE Rebooting Computing Week

6-10 Nov. 2017; Washington, DC, USA

Isaac Newton is reported to have said in 1676: "If I have seen further, it is by standing on the shoulders of giants." IEEE offers you another such opportunity in 2017.

Join us for the 2017 Rebooting Computing Week, featuring three events addressing the new era of technology and computing. The events include: International Roadmap for Devices and Systems (IRDS); IEEE International Conference on Rebooting Computing (ICRC); Industry Summit on the Future of Computing.

Registration is now open with discounts available for IEEE members. **Register** early to save!

#### VLSI-SoC 2017: PhD Forum

VLSI-SoC 2017's Ph.D. Forum is a poster session aimed at the exchange of ideas and experiences of Ph.D. students from different parts of the world. Elected Ph.D. students have an opportunity to discuss their thesis and research work with specialists within the system and design automation communities. This offers a good opportunity for students to receive valuable feedback and gain exposure in the job market. Furthermore, this forum also provides a great chance for industry officials to meet junior researchers, giving an avenue for incorporating the latest research developments into their companies.

#### **Topics of Interest:**

Topics of interest include but are not limited to: Analog, mixed-signal and sensor architectures; Digital architectures: NoC, multi-core, and reconfigurable; CAD: Synthesis and analysis; Prototyping, verification, modeling, and simulation; Circuits and systems for signal processing and communications; Embedded systems: Architecture, design, and software; Low-power and thermal-aware IC design; Emerging semiconductor technologies; Variability, reliability, and test; Hardware security.

For more information, please check: <a href="http://vlsisoc2017.ozyegin.edu.tr/phd-fo-rum/">http://vlsisoc2017.ozyegin.edu.tr/phd-fo-rum/</a>

#### After DATE 2017

The DATE 2017 Conference and Exhibition closed doors last Friday, March 31, 2017, receiving more than 1,500 registrations from over 50 countries and ending with excellent feedback from both participants and exhibitors. 2017 was a special year for the world's favourite electronic systems design and test conference, as the community celebrated its 20th edition and it was held for the first time in Switzerland, at the SwissTech Convention Center on the EPFL campus in Lausanne, from March 27 to 31.

For the 20th successive year, DATE presented an exciting technical programme, comprising 78 technical sessions and 11 Exhibition Theatre sessions. DATE started on Monday with nine in-depth tutorials and the popular PhD Forum, hosted by EDAA, ACM SIGDA, and IEEE CEDA.

CEDA Currents is a publication of IEEE CEDA. Please send contributions to José L. Ayala (currents@ieee-ceda.com).

On Tuesday, the conference was opened by the plenary keynote speakers Dr. Arvind Krishna from IBM and Dr. Doug Burger from Microsoft. In addition, a keynote lecture from Prof. Giovanni De Micheli (Professor at EPFL and Director of Nano-Tera.ch) was given on "Distributed Systems for Health and Environmental Monitoring" within the Nano-Tera.ch initiative. A special session was dedicated to Ralph Otten, pioneer of physical design, who prematurely died in an accident.

# Papers in IEEE Embedded Systems Letters

The top-five accessed articles from *IEEE Embedded Systems Letters* in May 2017 were as follows:

- "Public Key Authentication and Key Agreement in IoT Devices With Minimal Airtime Consumption," by S. Sciancalepore et al.
- "Testing Autonomous Vehicle Software in the Virtual Prototyping Environment," by B. Kim et al.
- "Energy Efficient Outdoor Light Monitoring and Control Architecture Using Embedded System," by Z. Kaleem, T.M. Yoon, and C. Lee
- "Arduino Debugger," by J. Dolinay et al.
- "A Formal Verification Methodology for FPGA-Based Stepper Motor Control," by S. Jabeen et al.

## Papers in IEEE Design and Test

The top-five accessed articles from *IEEE Design&Test* in May 2017 were as follows:

- "Recent Technology Advances of Emerging Memories," by Y. Chen et al
- "Post-Silicon Validation in the SoC <u>Era: A Tutorial Introduction</u>," by P. Mishra et al.
- "Reliable Nonvolatile Memories: Techniques and Measures," by S. Swami et al.
- "Computing in the Dark Silicon Era: Current Trends and Research Challenges," by M. Shafique et al.
- "Dark Memory and Accelerator-Rich System Optimization in the Dark Silicon Era," by A. Pedram et al.

Upcoming Conferences (Yao-Wen Chang, conferences@ieee-ceda.com <b>)</b>	
<u>PATMOS</u>	Aristotle University, Thessaloniki, Greece September 25-27
<u>FMCAD</u>	TU Wien, Vienna, Austria October 2-6
<u>ESWeek</u>	Seoul, South Korea October 15-20

Find us online at <a href="http://ieee-ceda.org">http://ieee-ceda.org</a>

IEEE Embedded Systems Letters is open for submissions. Visit mc.manuscriptcentral.com/les-ieee.

IEEE Design & Test is open for submissions. Visit mc.manuscriptcentral.com/dandt and ieee-ceda.org/publications/d-t/paper-submission.



#### IEEE COUNCIL ON ELECTRONIC DESIGN AUTOMATION

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